



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005

SUPPLIER INSPECTION SERVICES, INC.  
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CALIBRATION

Valid To: February 28, 2018

Certificate Number: 1390.01

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform the following calibrations<sup>1</sup>:

I. Dimensional

Parameter/Equipment	Range	CMC <sup>2,4</sup> (±)	Comments
Functional Gages –			
3D Measurements	Up to 35 in Up to 50 in Up to 90 in	25 µin + 8 µin/in 170 µin + 6 µin/in 340 µin + 12 µin/in	Zeiss CMM B&S CMM B&S CMM
3D Measurements <sup>3</sup>	Up to 96 in Up to 96 in	1200 µin + 7 µin/in 1800 µin + 5 µin/in	Faro arm w/ laser line scanner
2D Measurements	Up to 5 in Up to 4 in Up to 10 in	430 µin + 7 µin/in 350 µin + 19 µin/in 350 µin + 38 µin/in	Vision system contracer optical comparator
1D Measurements	Up to 3 in Up to 6 in Up to 12 in Up to 0.5 in Up to 0.5 in	130 µin + 7 µin/in 1100 µin + 18L µin/in 2100 µin + 18L µin/in 610 µin + 0.4D uin/in 0.0035 in	Micrometer Calipers Calipers Pins Radius gages
Angle	0° to 360°	0° 4' 20"	Optical comparator
Surface Roughness	(0 to 125) Ra	7.7 µin	Profilometer

## II. Dimensional Testing/Calibration<sup>1</sup>

Parameter/Equipment	Range	CMC <sup>2,4</sup> (±)	Comments
Manufactured Components <sup>5</sup> –			
3D Measurements	Up to 35 in Up to 50 in Up to 90 in	25 μin + 8 μin/in 170 μin + 6 μin/in 340 μin + 12 μin/in	Zeiss CMM B&S CMM B&S CMM
3D Measurements <sup>3</sup>	Up to 96 in Up to 96 in	1200 μin + 7 μin/in 1800 μin + 5 μin/in	Faro arm w/ laser line scanner
2D Measurements	Up to 5 in Up to 4 in Up to 10 in	430 μin + 7 μin/in 350 μin + 19 μin/in 350 μin + 38 μin/in	Vision system contracer optical comparator
1D Measurements	Up to 4 in Up to 6 in Up to 12 in Up to 0.5 in Up to 0.5 in	130 μin + 7 μin/in 1100 μin + 18L μin/in 2100 μin + 18L μin/in 610 μin + 0.4D uin/in 0.0035 in	Micrometer Calipers Calipers Pins Radius gages
Angle	0° to 360°	0° 4' 20"	Optical comparator
Surface Roughness	(0 to 125) Ra	7.7 μin	Profilometer

<sup>1</sup> This laboratory offers commercial dimensional testing/calibration service.

<sup>2</sup> Calibration and Measurement Capability Uncertainty (CMC) is the smallest uncertainty of measurement that a laboratory can achieve within its scope of accreditation when performing more or less routine calibrations of nearly ideal measurement standards or nearly ideal measuring equipment. CMC's represent expanded uncertainties expressed at approximately the 95 % level of confidence, usually using a coverage factor of  $k = 2$ . The actual measurement uncertainty of a specific calibration performed by the laboratory may be greater than the CMC due to the behavior of the customer's device and to influences from the circumstances of the specific calibration.

<sup>3</sup> Field calibration service is available for this calibration and this laboratory meets A2LA R104 – *General Requirements: Accreditation of Field Testing and Field Calibration Laboratories* for these calibrations. Please note the actual measurement uncertainties achievable on a customer's site can normally be expected to be larger than the CMC found on the A2LA Scope. Allowance must be made for aspects such as the environment at the place of calibration and for other possible adverse effects such as those caused by transportation of the calibration equipment. The usual allowance for the actual uncertainty introduced by the item being calibrated, (e.g. resolution) must also be considered and this, on its own, could result in the actual measurement uncertainty achievable on a customer's site being larger than the CMC.

<sup>4</sup> In the statement of CMC,  $D$  is the numerical value of the diagonal length of the device measured in inches;  $L$  is the numerical value of the nominal length of the device measured in inches.

<sup>5</sup> This laboratory meets R205 – *Specific Requirements: Calibration Laboratory Accreditation Program* for the types of dimensional tests listed above and is considered equivalent to that of a calibration.